### **Bump bonding**

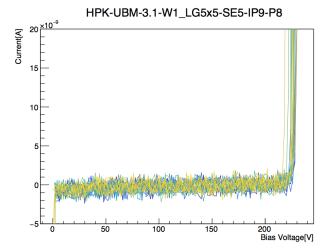
Liaoshan Shi

Apr. 18, 2019

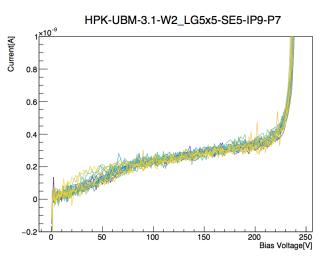
#### Introduction

- We sent two sensors and two ASIC chips to Institute of Microelectronics of CAS for bump bonding.
- Sensor information: HPK 5x5 with UBM, type 3.1 (50um, low doping)
  - EXX28995-WNo1 LG 5x5-SE5-IP9-P8
  - EXX28995-WNo2 LG 5x5-SE5-IP9-P7

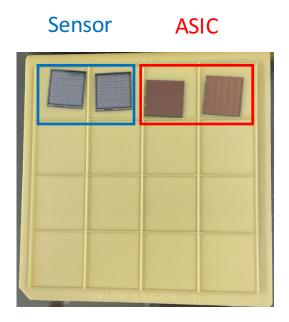
I-V before bump bonding (Expect similar performance between W1 and W2. The difference is mainly due to different measurement configurations):



W1 measured with low resolution configuration.

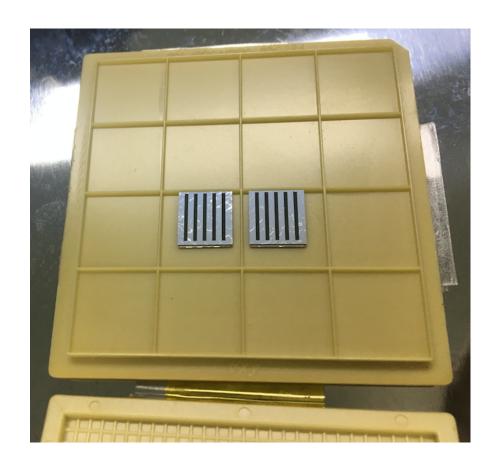


W2 measured with high resolution configuration.



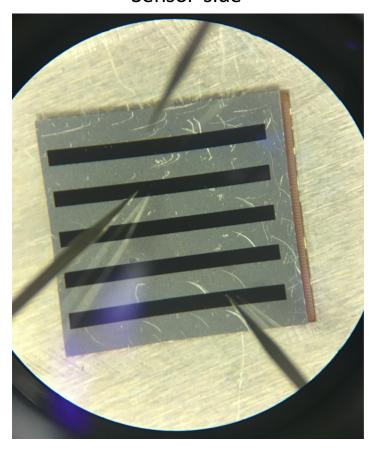
#### 硅传感器 ASIC芯片1 Layout DESTRUCTION OF THE PARTY OF THE 7500±40 6500 (P1300 x5) ASIC芯片1 9 9 9 9 传感器 Inner Guard Ring PAD2 (for UBM) 98 • 98 • 0 . 0 | 0 . 0 8 8 Psub PAD 60 x 200 6500 (P1300 x5) $7800 \pm 40$ AL open window 100 x 100 Active area PAD1 (for UBM) Active area PAD2 100 x 200 F-Inner Guard Ring PAD1 60 x 200 800±40 PIN 5x5-SE5-IP9-UBN

# After bump bonding

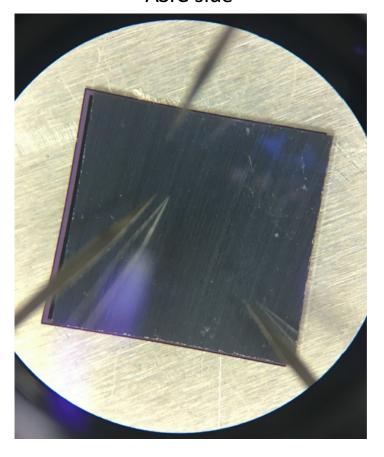


## Sensor 1 after bump bonding

Sensor side



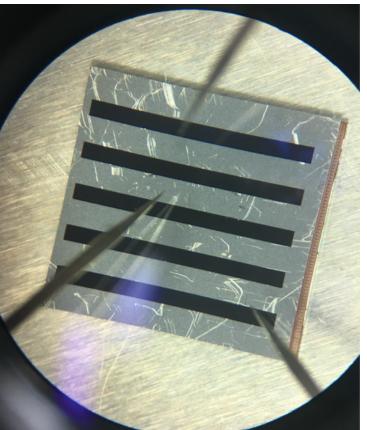
ASIC side



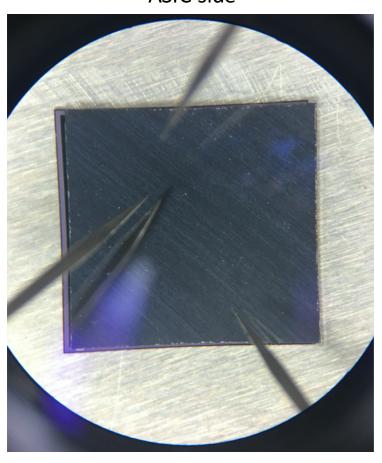
### Sensor 2 after bump bonding







ASIC side



The sensor is not perfectly parallel to the ASIC. We can see a small tilt angle by comparing their edges. Suggest to perform an ultrasonic scan to check the bonding quality.